

# Ultraviolet photodetection with gallium nitride nanoflowers on silicon

**Researchers claim the highest responsivity over both GaN/Si and commercial silicon devices.**

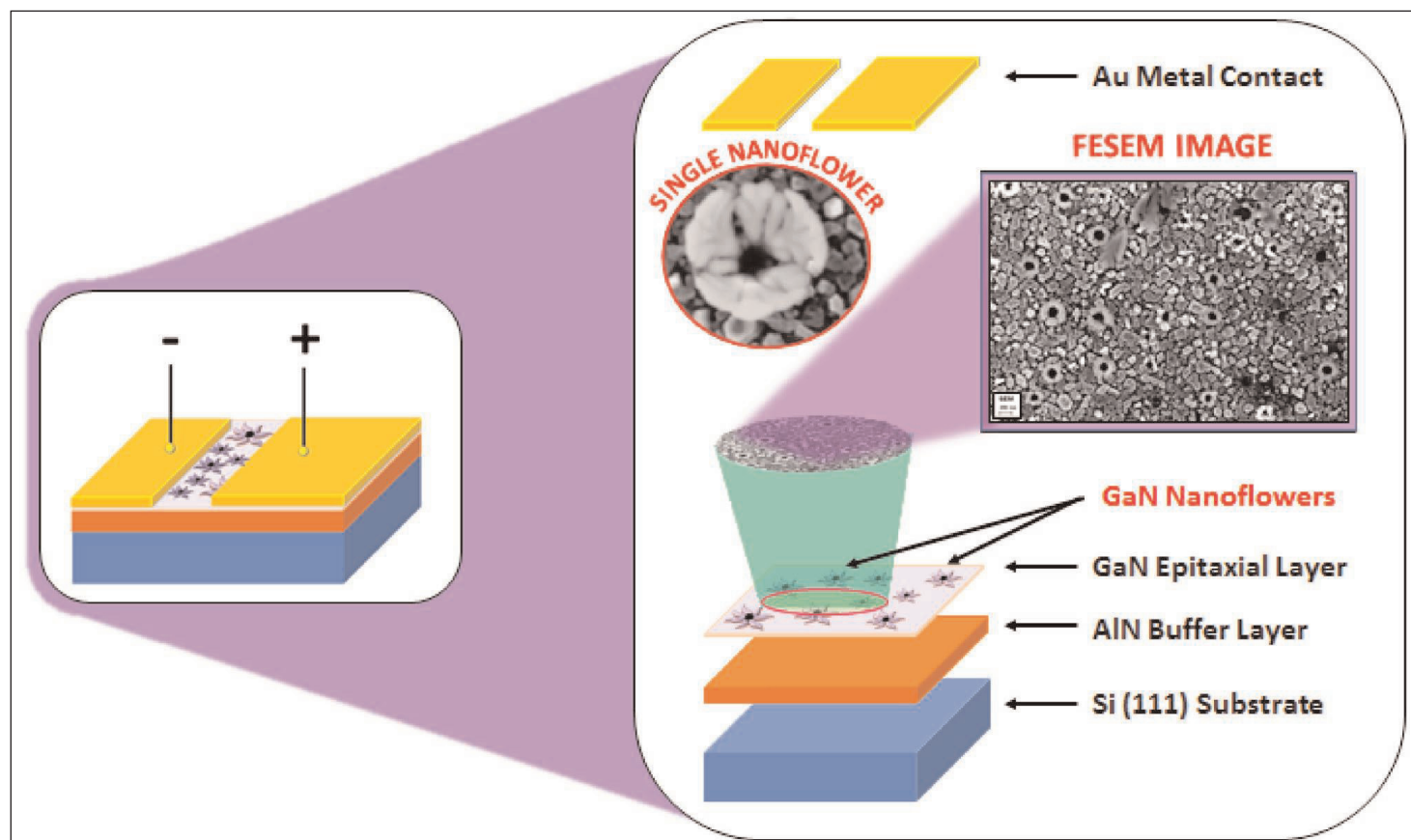
India's CSIR-National Physical Laboratory (CSIR-NPL) has developed gallium nitride (GaN) nanoflower (NF) structures on silicon as metal-semiconductor-metal ultraviolet (UV) photodetectors (PDs) [Neha Aggarwal et al, *Adv. Electron. Mater.*, vol3, p1700036, 2017]. The team claims: "The reported responsivity is the highest among the GaN UV photodetectors on Si substrates and commercially available silicon-based UV photodetectors."

The researchers see potential visible-blind UV applications in instrumentation for solar UV monitoring, astronomy, highly secure space-to-space communications, biological sensors, and military uses such as missile detection.

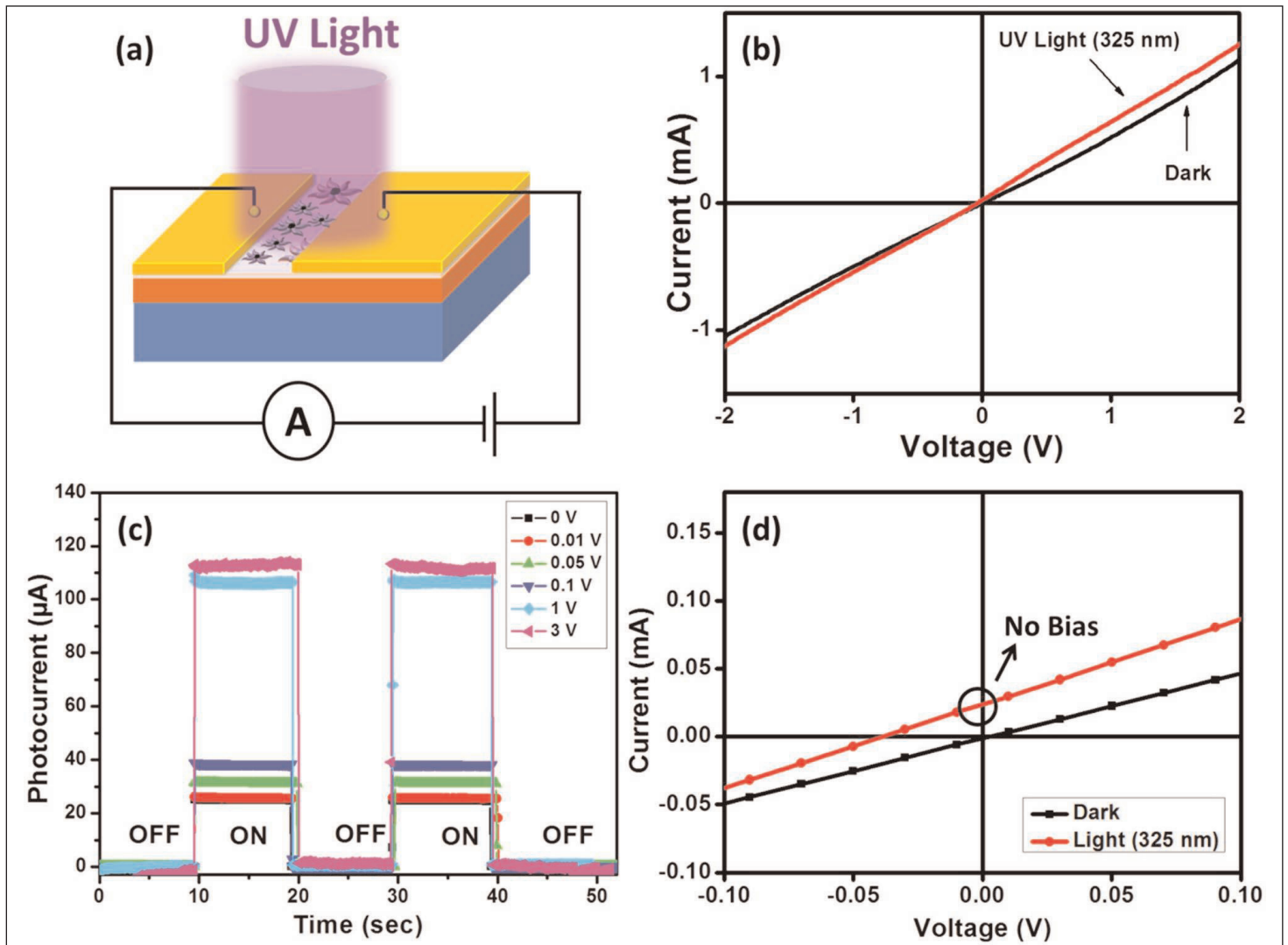
III-nitride materials offer advantages over silicon photodetectors in terms of cut-off wavelength tunability, high thermal stability, high electron saturation velocity, small dielectric constant, and high breakdown field.

The GaN nanoflowers were grown by plasma-assisted molecular beam epitaxy (PAMBE) on a 30nm 825°C aluminium nitride buffer on (111) silicon (Figure 1). The GaN growth began with an 80nm thin layer followed by the nanoflowers. The GaN growth temperature was 730°C.

The photodetector electrodes were gold/chromium (150nm/5nm). Nanoflower density was  $8.8 \times 10^7 / \text{cm}^2$ . The nanoflower structure had a  $\sim 200\text{nm}$  diameter at the base, opening up to 300–450nm at the top.



**Figure 1. Fabricated device and exploded model representing field emission secondary electron microscopy image of epitaxial GaN film as well as nanoflowers in grown heterostructure.**



**Figure 2. (a) Layout of GaN nanoflower-based UV photodetector device under UV illumination. (b) Current-voltage characteristics under dark and UV light conditions. (c) Time-correlated response of photocurrent**

The devices were tested under 325nm UV light. The dark current leakage was attributed to thermionic emission, which increased with the applied bias.

The researchers also found a photocurrent at zero bias. This photocurrent was attributed to the effects of different size electrodes leading to a tilt in the depletion layer inducing charge separation and transport. In particular, a large electrode attracts more photo-generated holes, reducing the barrier height.

The response at zero bias was 132mA/W with 325nm UV of 13mW power. The researchers comment: "The value stated at no bias in the present study is significantly higher than the recently reported self-driven GaN-based photodetector which shows the photosponsivity of 0.037, 0.083, and 0.104AW<sup>-1</sup> using different contact electrodes and a flexible self-powered GaN UV photo-switch which possesses responsivities of 0.03 and 0.0116AW<sup>-1</sup> at the power density of  $\approx 3.5$  and 35mWcm<sup>-2</sup>, respectively."

The response to 13W UV power pulsed at 10s intervals showed a zero-bias light-to-dark current ratio of 260. The dark current was 90nA. The detectivity —

(response (132mA/W)  $\times$  (active area)<sup>1/2</sup>)/(2  $\times$  (electron charge)  $\times$  (dark current))<sup>1/2</sup> — was 2.4 $\times 10^{10}$ Jones. The rise time was 63ms and the fall time 27ms.

Lower-power illumination of 1mW resulted in a higher response of 10.5A/W. The researchers say that this response level is higher than for commercially available UV photodetectors.

A comparison planar GaN photodetector had a maximum photocurrent of 25.9mA — a 1.5A/W response — at 1V bias under 1mW illumination.

The increased response for GaN NFs is attributed to their higher surface-to-volume ratio, giving a higher rate for absorption of photons and generation of electrons and holes.

The planar device had a noise equivalent power of 60pW/Hz<sup>1/2</sup>, which is much higher than the 1.2pW/Hz<sup>1/2</sup> value found for the photodetectors using GaN nanoflowers. The researchers attribute the lower noise in the GaN nanoflower photodetectors to the reduction of stress and defect states. ■

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